

FaultTM: Error Detection and Recovery Using Hardware Transactional Memory

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Publication: ACM/IEEE Design, Automation, and Test in Europe (DATE)

Place Published: Grenoble, France

Barcelona Supercomputing Center - Centro Nacional de Supercomputación

Source URL (retrieved on 16 Mar 2025 - 00:09): <https://www.bsc.es/es/node/40582>